TOSHIBA Power MOS FET Module Silicon N&P Channel MOS Type (Four L^2-π-MOSV in One)

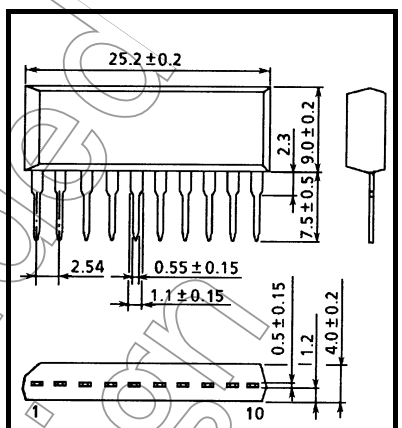
MP4212

Industrial Applications

High Power High Speed Switching Applications
H-Switch Driver

- 4-V gate drivability
- Small package by full molding (SIP 10 pin)
- High drain power dissipation (4-device operation)
  : P_T = 4 W (Ta = 25°C)
- Low drain-source ON resistance: $R_{DS\ (ON)}$ = 120 mΩ (typ.) (N-ch)
  160 mΩ (typ.) (P-ch)
- High forward transfer admittance: $|Y_{fs}|$ = 5.0 S (typ.) (Nch)
  4.0 S (typ.) (Pch)
- Low leakage current: I_{GSS} = ±10 μA (max) (V_{GS} = ±16 V)
  I_{DSS} = 100 μA (max) (V_{DS} = 60 V)
- Enhancement-mode: V_{th} = 0.8 to 2.0 V (V_{DS} = 10 V, I_D = 1 mA)

Unit: mm



1, 10 SOURCE
2, 4, 6, 8 GATE
3, 5, 7, 9 DRAIN
(PIN 1 AND PIN 10 IS DISCONNECTED INTERNALLY)

JEDEC	—
JEITA	—
TOSHIBA	2-25A1C

Weight: 2.1 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating		Unit
			Nch	Pch	
Drain-source voltage		V_{DSS}	60	−60	V
Drain-gate voltage (R_{GS} = 20 kΩ)		V_{DGR}	60	−60	V
Gate-source voltage		V_{GSS}	±20	±20	V
Drain current	DC	I_D	5	−5	A
	Pulse	I_{DP}	20	−20	
Drain power dissipation (1-device operation, Ta = 25°C)		P_D	2.0		W
Drain power dissipation (4-device operation, Ta = 25°C)		P_{DT}	4.0		W
Single pulse avalanche energy (Note 1)		E_{AS}	129	273	mJ
Avalanche current		I_{AR}	5	−5	A
Repetitive avalanche energy (Note 2)	1-device operation	E_{AR}	0.2		mJ
	4-device operation	E_{ART}	0.4		
Channel temperature		T_{ch}	150		°C
Storage temperature range		T_{stg}	−55 to 150		°C

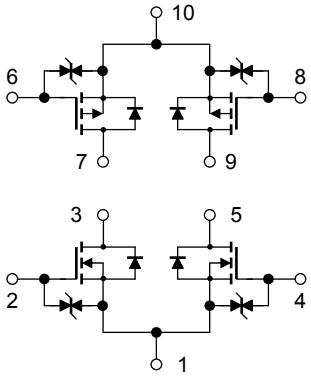
Note 1: Condition fo avalanche energy (single pulse) measurement
Nch: V_{DD} = 25 V, starting T_{ch} = 25°C, L = 7 mH, R_G = 25 Ω, I_{AR} = 5 A
Pch: V_{DD} = −25 V, starting T_{ch} = 25°C, L = 14.84 mH, R_G = 25 Ω, I_{AR} = −5 A

Note 2: Repetitive rating; pulse width limited by maximum channel temperature

Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Please handle with caution.

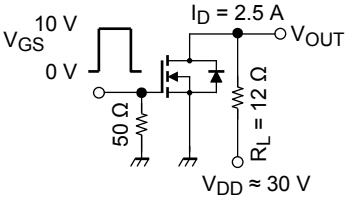
Array Configuration



Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance from channel to ambient (4-device operation, Ta = 25°C)	$\Sigma R_{th\ (ch\text{-}a)}$	31.2	°C/W
Maximum lead temperature for soldering purposes (3.2 mm from case for t = 10 s)	T_L	260	°C

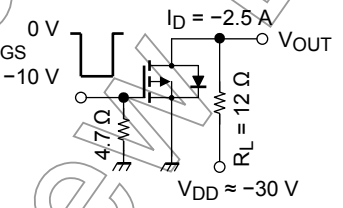
Electrical Characteristics (Ta = 25°C) (Nch MOS FET)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	—	—	±10	μA
Drain cut-off current		I_{DSS}	V_{DS} = 60 V, V_{GS} = 0 V	—	—	100	μA
Drain-source breakdown voltage		$V_{(BR)\ DSS}$	I_D = 10 mA, V_{GS} = 0 V	60	—	—	V
Gate threshold voltage		V_{th}	V_{DS} = 10 V, I_D = 1 mA	0.8	—	2.0	V
Drain-source ON resistance		$R_{DS\ (ON)}$	V_{GS} = 4 V, I_D = 2.5 A	—	0.21	0.32	Ω
			V_{GS} = 10 V, I_D = 2.5 A	—	0.12	0.16	
Forward transfer admittance		$\|Y_{fs}\|$	V_{DS} = 10 V, I_D = 2.5 A	3.0	5.0	—	S
Input capacitance		C_{iss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz	—	370	—	pF
Reverse transfer capacitance		C_{rss}		—	60	—	pF
Output capacitance		C_{oss}		—	180	—	pF
Switching time	Rise time	t_r		—	18	—	ns
	Turn-on time	t_{on}		—	25	—	
	Fall time	t_f		—	55	—	
	Turn-off time	t_{off}	V_{IN}: t_r, t_f < 5 ns, duty ≤ 1%, t_w = 10 μs	—	170	—	
Total gate charge (Gate-source plus gate-drain)		Q_g	V_{DD} ≈ 48 V, V_{GS} = 10 V, I_D = 5 A	—	12	—	nC
Gate-source charge		Q_{gs}		—	8	—	nC
Gate-drain (“miller”) charge		Q_{gd}		—	4	—	nC

Source-Drain Diode Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current	I_{DR}	—	—	—	5	A
Pulse drain reverse current	I_{DRP}	—	—	—	20	A
Diode forward voltage	V_{DSF}	I_{DR} = 5 A, V_{GS} = 0 V	—	—	−1.7	V
Reverse recovery time	t_{rr}	I_{DR} = 5 A, V_{GS} = 0 V		70	—	ns
Reverse recovery charge	Q_{rr}	dI_{DR}/dt = 50 A/μs	—	0.1	—	μC

Electrical Characteristics (Ta = 25°C) (Pch MOS FET)

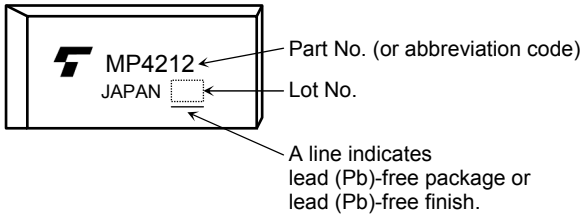
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	—	—	±10	μA
Drain cut-off current		I_{DSS}	V_{DS} = −60 V, V_{GS} = 0 V	—	—	−100	μA
Drain-source breakdown voltage		$V_{(BR)\ DSS}$	I_D = −10 mA, V_{GS} = 0 V	−60	—	—	V
Gate threshold voltage		V_{th}	V_{DS} = −10 V, I_D = −1 mA	−0.8	—	−2.0	V
Drain-source ON resistance		$R_{DS\ (ON)}$	V_{GS} = −4 V, I_D = −2.5 A	—	0.24	0.28	Ω
			V_{GS} = −10 V, I_D = −2.5 A	—	0.16	0.19	
Forward transfer admittance		$\|Y_{fs}\|$	V_{DS} = −10 V, I_D = −2.5 A	2.0	4.0	—	S
Input capacitance		C_{iss}	V_{DS} = −10 V, V_{GS} = 0 V, f = 1 MHz	—	630	—	pF
Reverse transfer capacitance		C_{rss}		—	95	—	pF
Output capacitance		C_{oss}		—	290	—	pF
Switching time	Rise time	t_r		—	25	—	ns
	Turn-on time	t_{on}		—	45	—	
	Fall time	t_f		—	55	—	
	Turn-off time	t_{off}		—	200	—	
Total gate charge (gate-source plus gate-drain)		Q_g	V_{DD} ≈ −48 V, V_{GS} = −10 V, I_D = −5 A	—	22	—	nC
Gate-source charge		Q_{gs}		—	16	—	nC
Gate-drain (“miller”) charge		Q_{gd}		—	6	—	nC

VIN: t_r, t_f < 5 ns, duty ≤ 1%, t_w = 10 μs

Source-Drain Diode Ratings and Characteristics (Ta = 25°C)

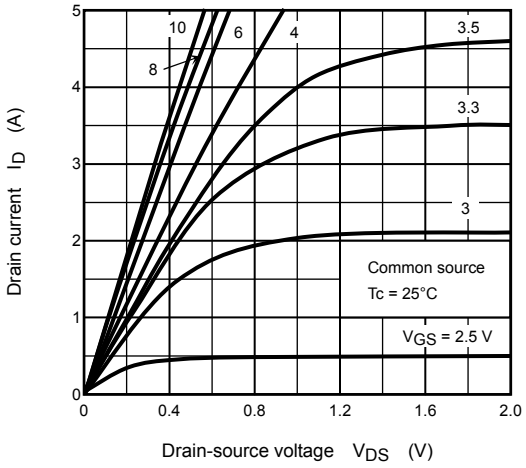
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current	I_{DR}	—	—	—	−5	A
Pulse drain reverse current	I_{DRP}	—	—	—	−20	A
Diode forward voltage	V_{DSF}	I_{DR} = −5 A, V_{GS} = 0 V	—	—	1.7	V
Reverse recovery time	t_{rr}	I_{DR} = −5 A, V_{GS} = 0 V	—	80	—	ns
Reverse recovery charge	Q_{rr}	dI_{DR}/dt = 50 A/μs	—	0.1	—	μC

Marking

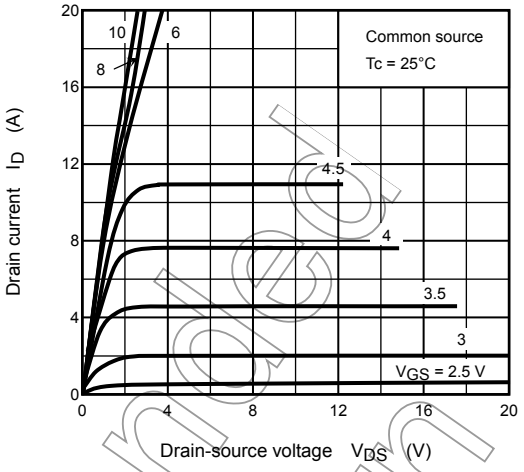


Nch MOS FET

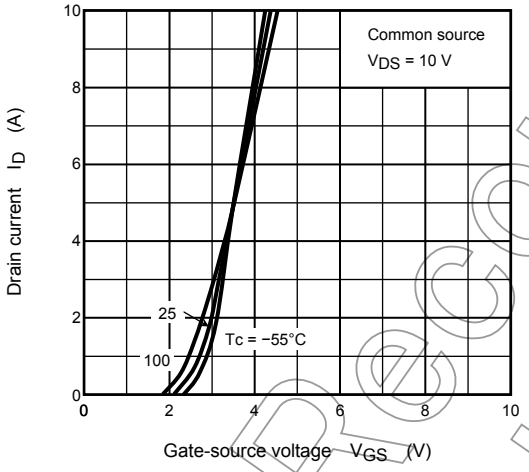
$I_D - V_{DS}$



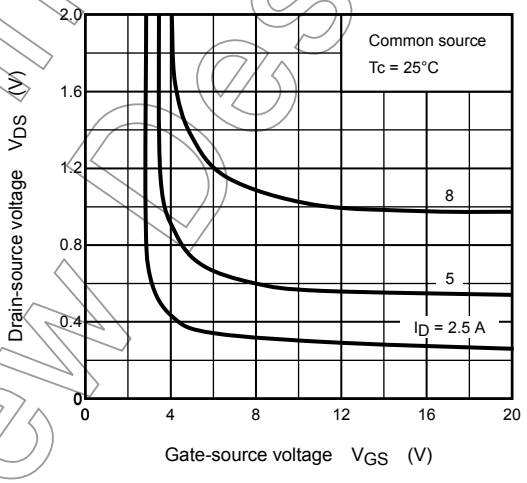
$I_D - V_{DS}$



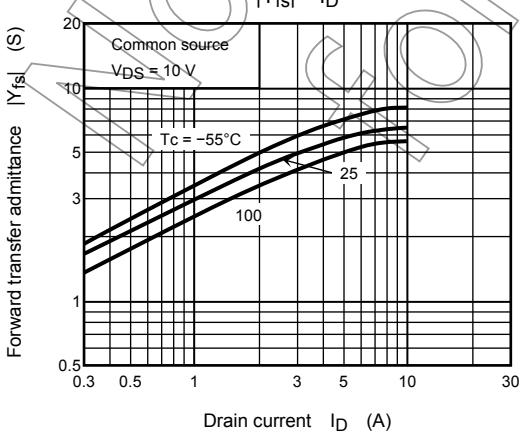
$I_D - V_{GS}$



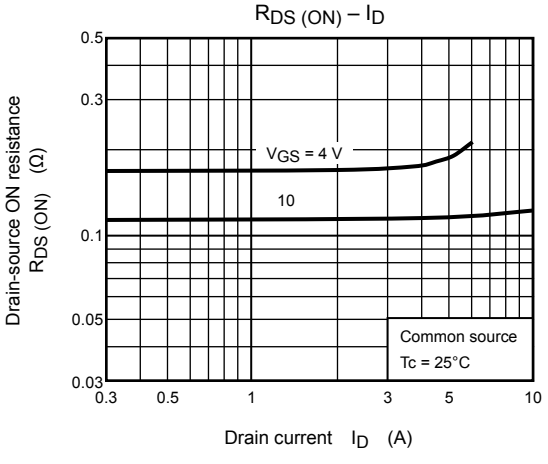
$V_{DS} - V_{GS}$



$|Y_{fs}| - I_D$

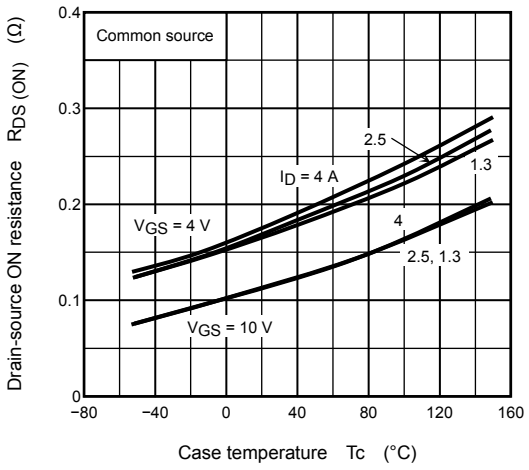


$R_{DS\ (ON)} - I_D$

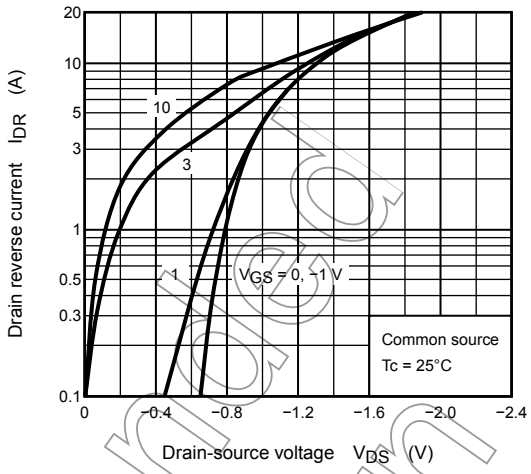


Nch MOS FET

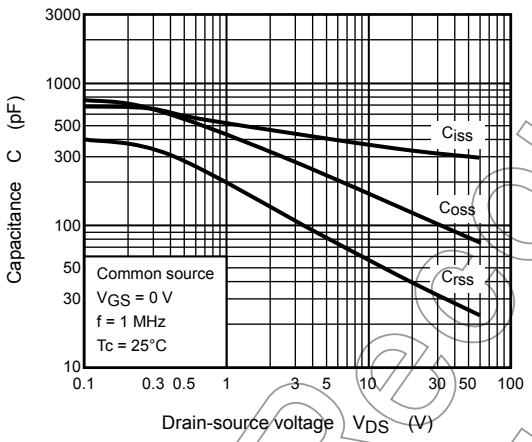
$R_{DS\ (ON)}$ – Tc



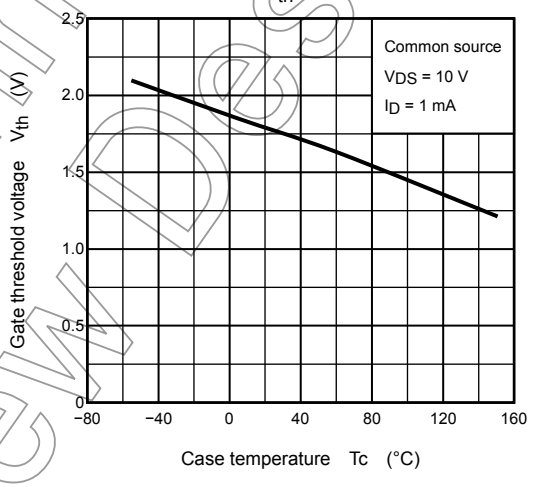
I_{DR} – V_{DS}



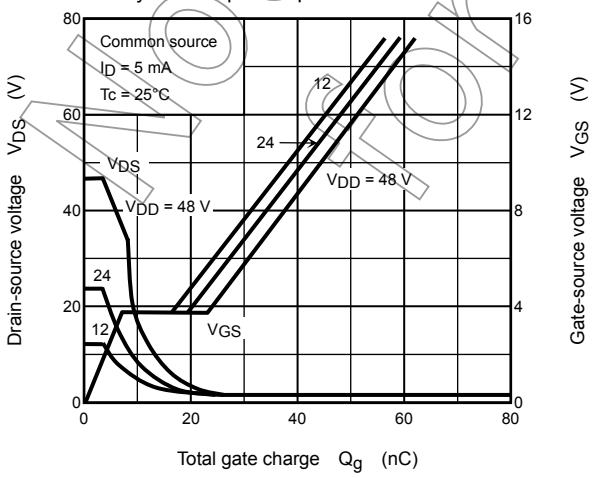
Capacitance – V_{DS}



V_{th} – Tc

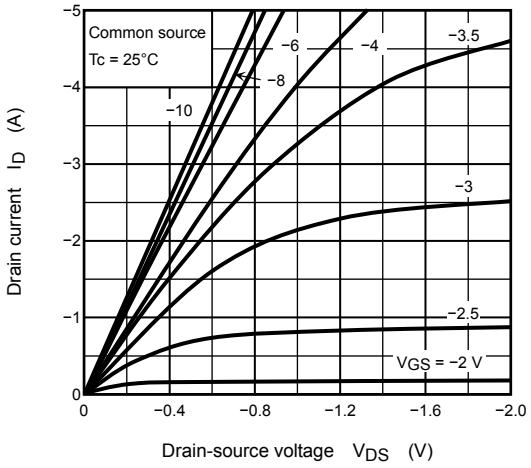


Dynamic Input/Output Characteristics

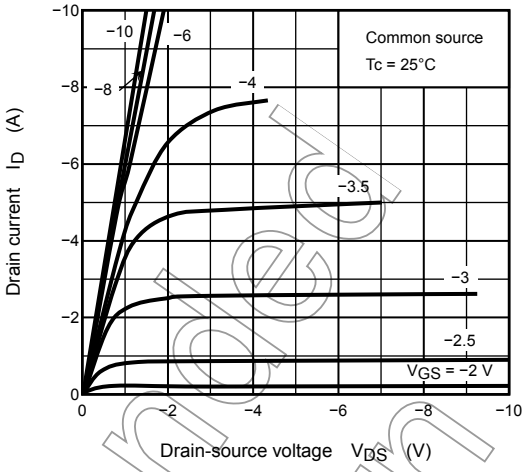


Pch MOS FET

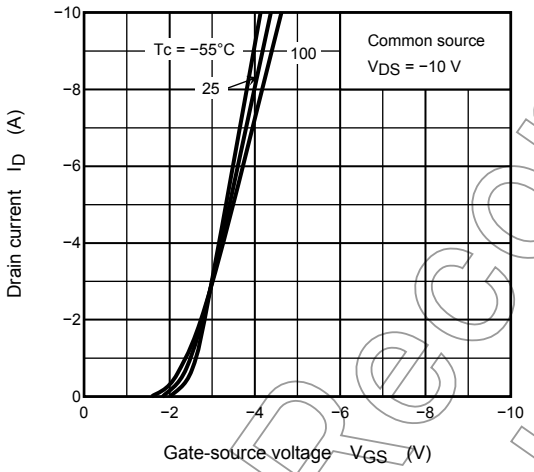
$I_D - V_{DS}$



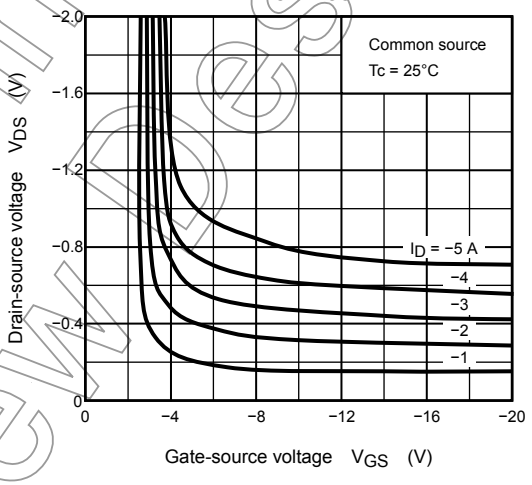
$I_D - V_{DS}$



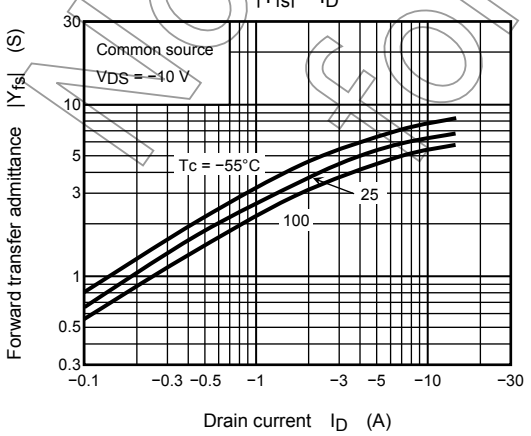
$I_D - V_{GS}$



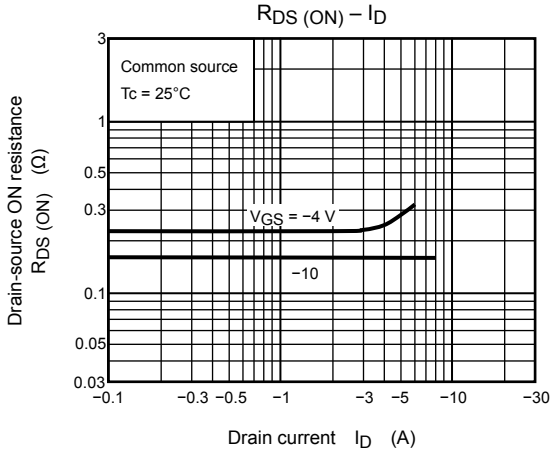
$V_{DS} - V_{GS}$



$|Y_{fs}| - I_D$

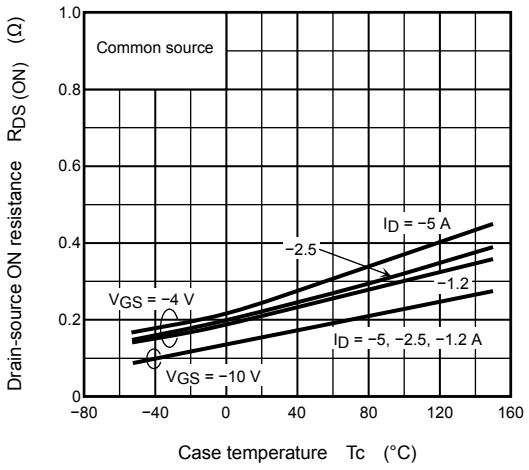


$R_{DS\ (ON)} - I_D$

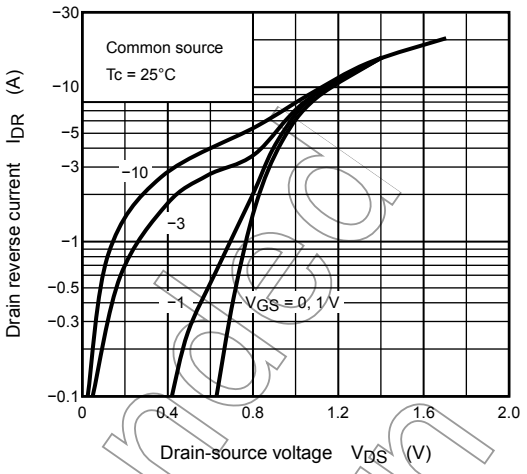


Pch MOS FET

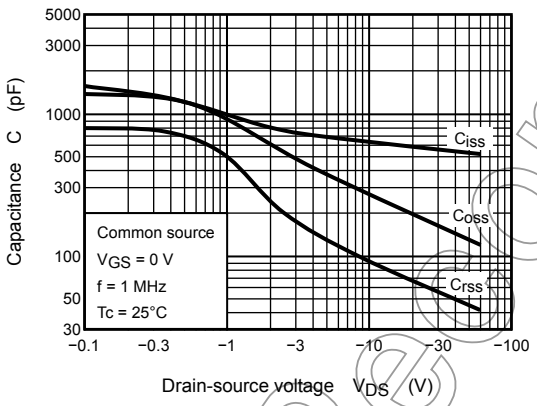
$R_{DS\ (ON)}$ – Tc



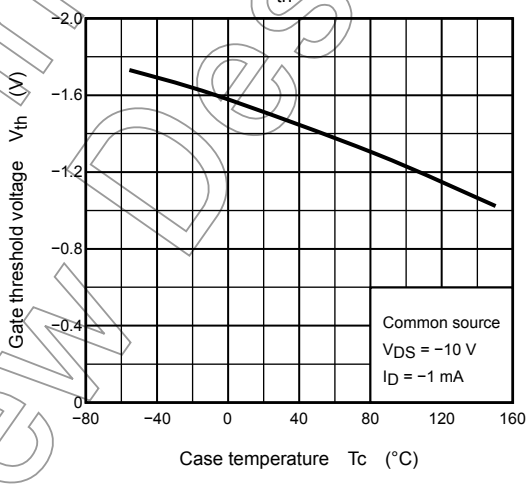
I_{DR} – V_{DS}



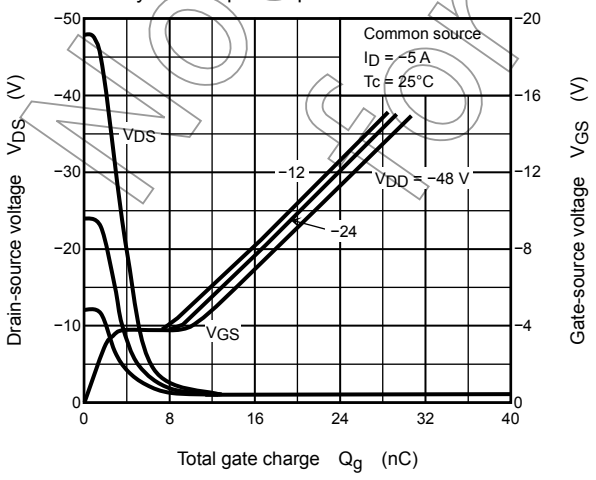
Capacitance – V_{DS}



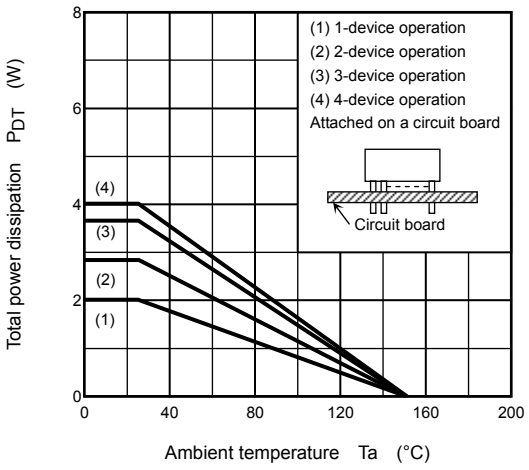
V_{th} – Tc



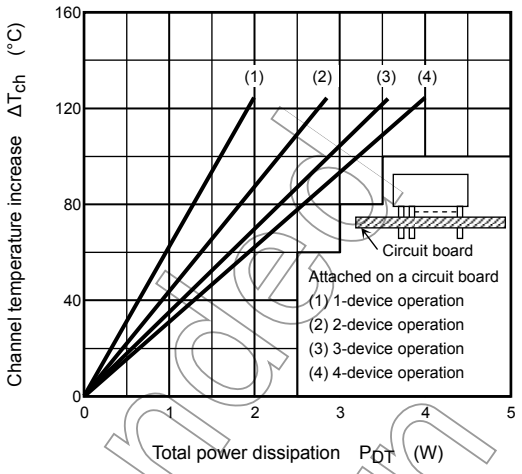
Dynamic Input/Output Characteristics



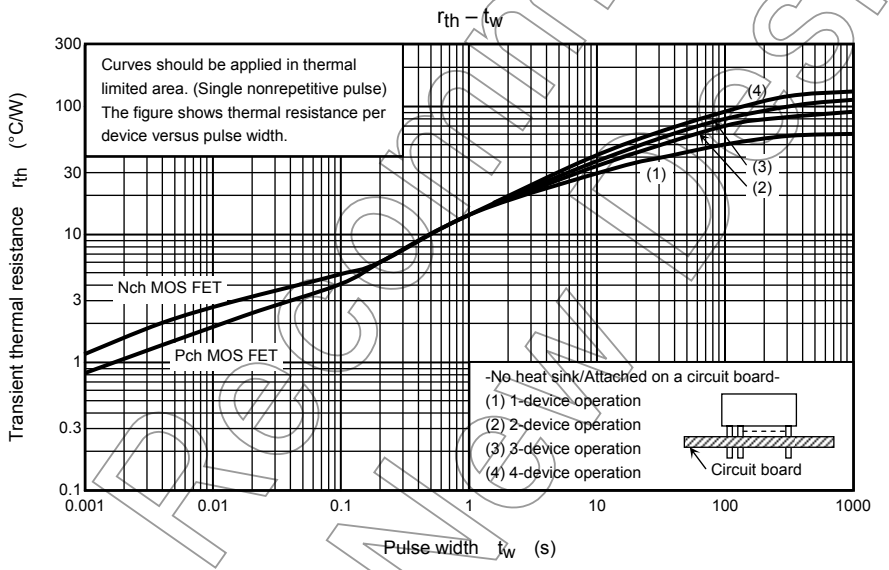
P_{DT} – Ta



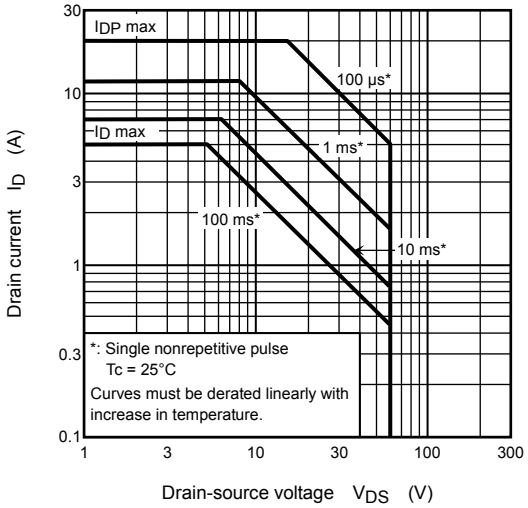
ΔT_{ch} – P_{DT}



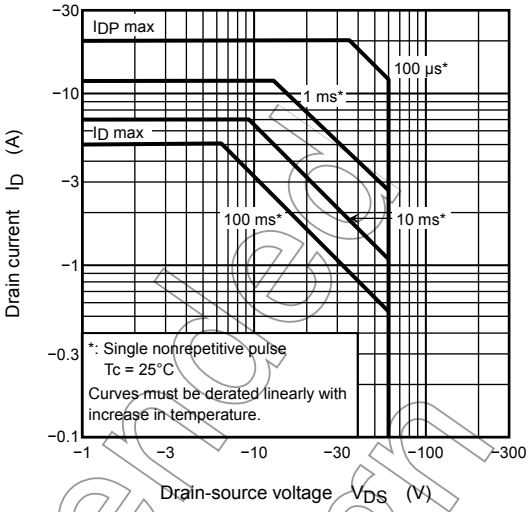
r_{th} – t_w



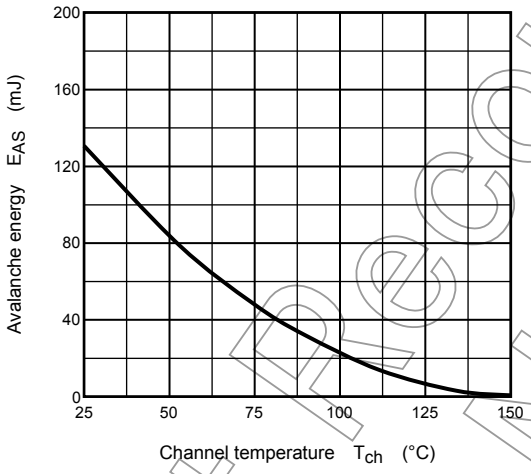
Safe Operating Area
(be applicable to Nch MOS FET)



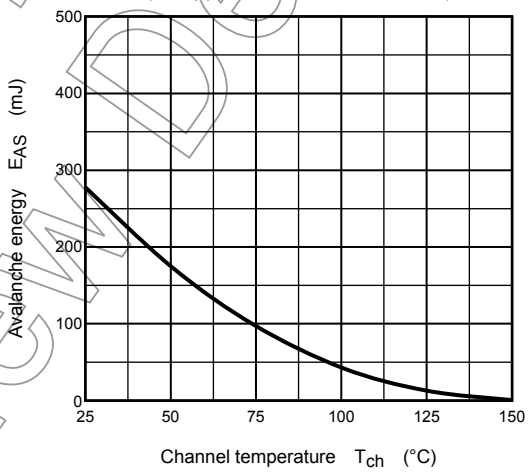
Safe Operating Area
(be applicable to Pch MOS FET)

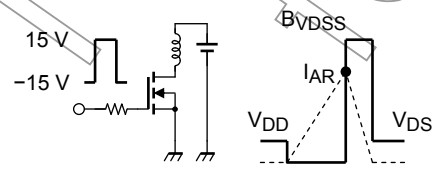


$E_{AS} - T_{ch}$
(be applicable to Nch MOS FET)



$E_{AS} - T_{ch}$
(be applicable to Pch MOS FET)

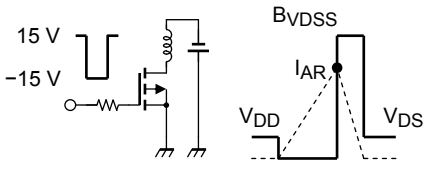




TEST CIRCUIT TEST WAVE FORM

Peak I_{AR} = 5 A, R_G = 25 Ω
V_{DD} = 25 V, L = 7 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$



TEST CIRCUIT TEST WAVE FORM

Peak I_{AR} = −5 A, R_G = 25 Ω
V_{DD} = −25 V, L = 14.84 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

RESTRICTIONS ON PRODUCT USE

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the “Handling Guide for Semiconductor Devices,” or “TOSHIBA Semiconductor Reliability Handbook” etc.
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